Se	earch Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/660,576	HONG, CHI-JEN
Examiner	Art Unit
TAN TRINH	2684

	SEARCHED		
Class	Subclass	Date	Examiner
455	566	6/12/2006	тт
	575.1		
	412		
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	414		
	426		
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INI	INTERFERENCE SEARCHED		
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SEA (INCLUDING	ARCH NOTES SEARCH STRATEGY	')
	DATE	EXMR
EAST	6/12/2006	TT
DANH LE	6/12/2006	тт
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